

Invention description to certificate of authorship.

The way of determination of non-linearity of an index of refraction of optical medium.

(19) SU (11) 1326962 A1

(51) 4 G 01 N 21/41

(21) 4046875/31-25

(22) 31.03.86

(46) 30.07.87 bulletin # 28

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(53) 535.024 (088.8)

Invention claims: Way of definition of nonlinearity of an index of refraction of optical medium consisting in that they shape an exploratory elliptical polarized light wave, route it into a researched sample, register an angle α_m of rotation of the ellipse of polarization of a wave, passed the researched sample distinguished of subjects, that with the purpose of rise of self-descriptiveness of a way at the expense of a possibility of joint definition of nonlinearity factors of an index of refraction of the researched environment for linearly polarized light n_{2l} and light, polarized on a circle n_{2k} a part of a elliptical polarized wave route to a standard sample, register an angle α_m of rotation of the ellipse of polarization of a wave, passed standard sample, then at the same time pass through a researched sample towards one another two additional elliptical polarized wave with equal intensity, register a critical angle α_p of rotational displacement of the ellipse of exploratory elliptical polarized light wave, passed through a researched sample, and the nonlinearity factors of an index of refraction of the researched environment for linearly polarized

light n and light, polarized on by the circle n , determine under the following formulas:

$$n_{2l} = \frac{12\pi \cdot \alpha_m \cdot K \cdot \chi_e \cdot (5 + \cos 2\alpha_p)}{n_{0e} \cdot \alpha_e \cdot (1 - K) \cdot l_m (1 - \cos 2\alpha_p)} \cdot \chi_e^{1221};$$

$$n_{2k} = \frac{24\pi \cdot \alpha_m \cdot K \cdot \chi_e \cdot (2 + \cos 2\alpha_p)}{n_{0e} \cdot \alpha_e \cdot (1 - K) \cdot l_m (1 - \cos 2\alpha_p)} \cdot \chi_e^{1221},$$

Where:

n_{0e} - linear index of refraction of the standard medium.

χ_e^{1221} - multiplier of tensor of non-linearity sensitivity of standard medium.

K - the part of light energy directed to the standard sample.

α_m - length of investigated sample.

α_e - length of standard sample.